

Summary: Fourier Analysis

model: $\mu(t) = \mu_0 + \sum_k c_k \cos \omega_k t + s_k \sin \omega_k t$

even spacing: $t_i = t_0 + i\Delta t \quad T = N\Delta t \quad i = 1, 2, \dots, N$

Fourier frequencies: $\omega_k = k\Delta\omega = 2\pi/P_k \quad P_k = T/k \quad k = 0, 1, \dots, K_{\max} = N/2$

Nyquist frequency: $\omega_{Nyq} = \pi/\Delta t = 2\pi/P_{Nyq} \quad P_{Nyq} = 2\Delta t$

Orthogonal basis: $\underline{C}_k = \cos \omega_k t \quad \underline{S}_k = \sin \omega_k t$

Model: $\underline{\mu} = \mu_0 \underline{C}_0 + \sum_{k=1}^N (c_k \underline{C}_k + s_k \underline{S}_k)$

Exact fit possible by using N parameters to fit N data points.

Badness-of-fit: $\chi^2 = \|\underline{X} - \underline{\mu}\|^2$

Optimal fit: $\hat{\mu}_0 = \frac{\underline{X} \cdot \underline{C}_0}{\underline{C}_0 \cdot \underline{C}_0} \quad \hat{c}_k = \frac{\underline{X} \cdot \underline{C}_k}{\underline{C}_k \cdot \underline{C}_k} \quad \hat{s}_k = \frac{\underline{X} \cdot \underline{S}_k}{\underline{S}_k \cdot \underline{S}_k}$

Power spectrum: $P(\omega_k) = \hat{A}_k^2 = \hat{c}_k^2 + \hat{s}_k^2$

Decomposes lightcurve into frequency components.

Wavelet Analysis - Wavelet Basis Functions

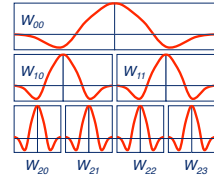
Fourier basis isolates in frequency but not in time.
Wavelet basis isolates in both frequency and time.

Exact fit possible by using N parameters to fit N data points.

$$W_{k,j}(x) = W[2^k(x-j)]$$

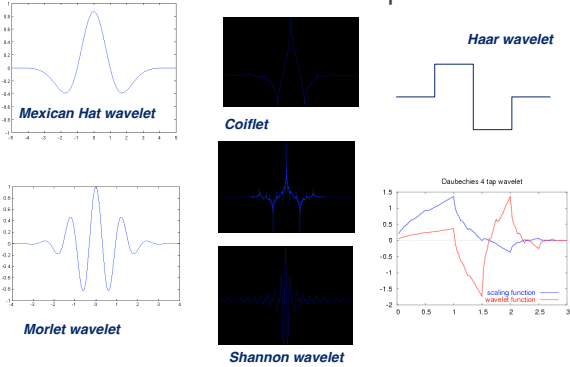
$$j = 0, \dots, (2^k - 1)$$

Many wavelet shapes possible. e.g. "Mexican Hat" wavelet



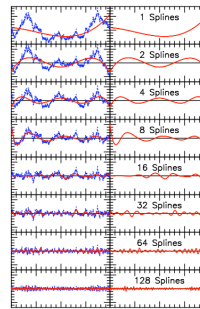
At each new level, $k \rightarrow k+1$:
Double the wavelet frequency.
Double the number of wavelets.
Complete orthogonal basis.

Various Wavelet Shapes

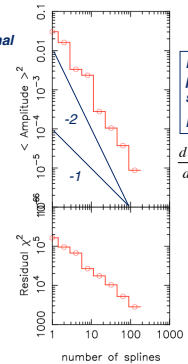


Spline Decomposition - Red Noise

Fit and subtract sequence of cubic splines.



Orthogonal spline basis.



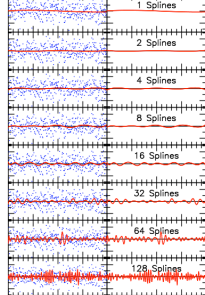
Red noise power spectrum.
Power law

$$\frac{d \text{Power}}{d \ln(\omega)} \propto \omega^{-2}$$

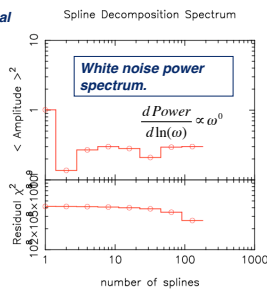
Red Noise: Random walk

Spline Decomposition - White Noise

Fit and subtract sequence of cubic splines.



Orthogonal spline basis.



White noise power spectrum.

$$\frac{d \text{Power}}{d \ln(\omega)} \propto \omega^0$$

White Noise: Independent noise at each time

Cross-correlation

- Cross-correlation function (CCF) used to measure the position (and strength) of a feature in the data.
- Pattern $P(x)$ matched in width (and shape) to the feature being measured.
- Shift the pattern by an offset s , and scale it to fit the data D_i with error bars σ_i measured at positions X_i :

$$CCF(s) = \frac{\sum_i P(X_i - s) D_i / \sigma_i^2}{\sum_i P^2(X_i - s) / \sigma_i^2}$$

Optimal scaling, yet again!

$$\text{Var}[CCF(s)] = \frac{1}{\sum_i P^2(X_i - s) / \sigma_i^2}$$

Note CCF errors are correlated.

- Good fit: $\chi^2_{\min} \sim N$. Get $\sigma(s)$ from $\Delta\chi^2 = 1$.

- CCF analysis fits a non-linear model to the data. Should minimise χ^2 , rather than maximising CCF.

Noisy data $D_i \pm \sigma_i$

Shifted patterns $P(x-s)$

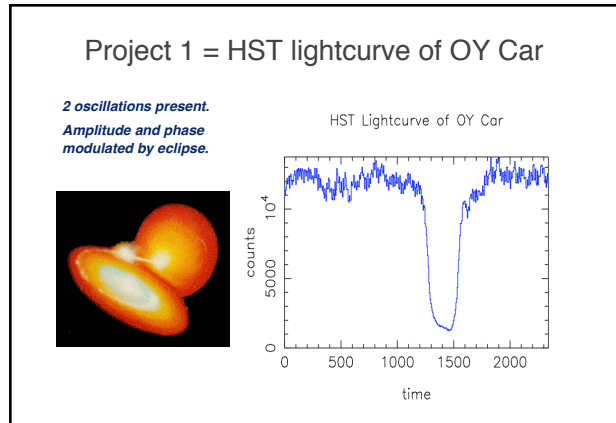
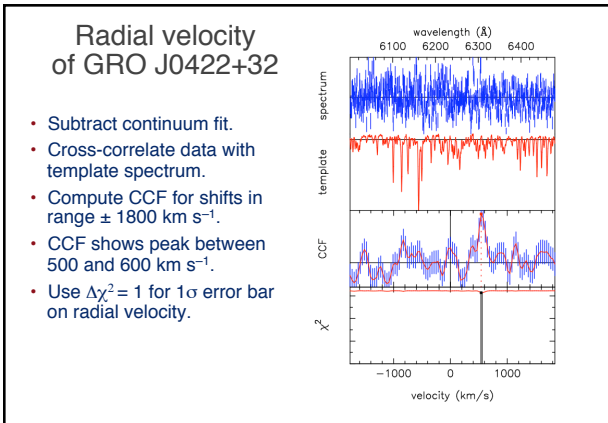
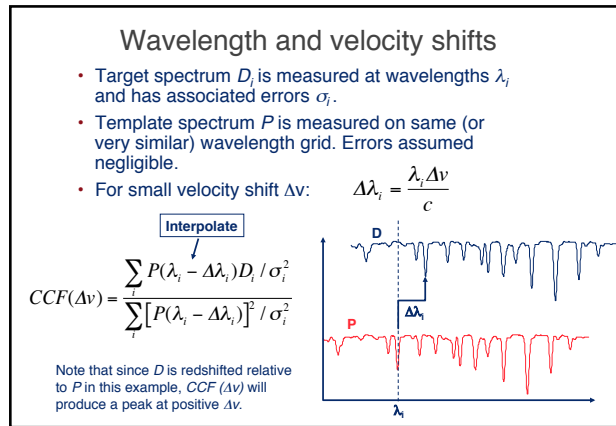
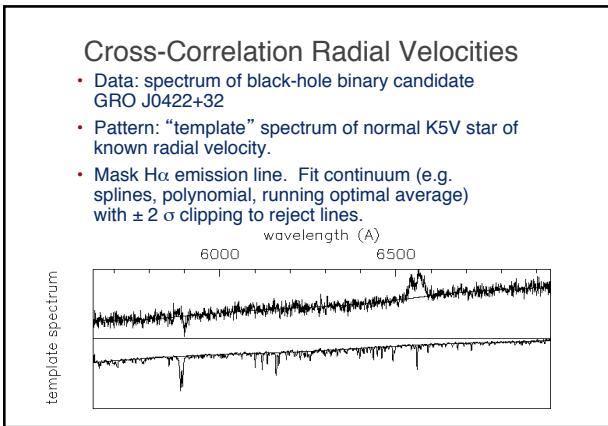
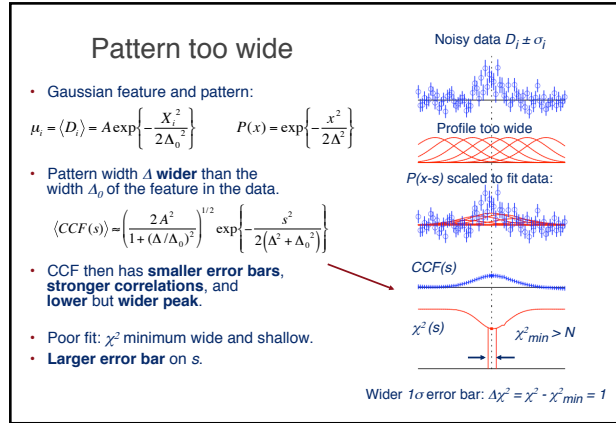
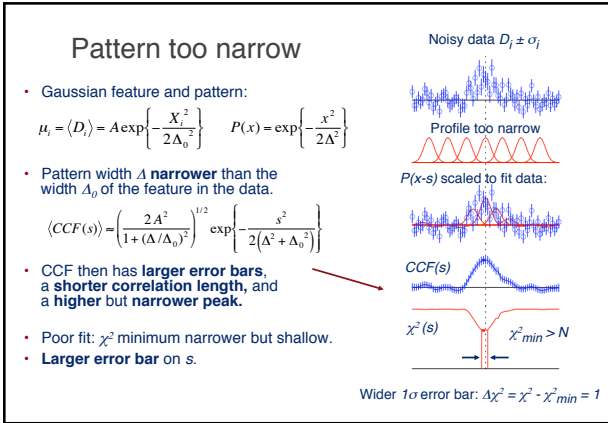
$P(x-s)$ scaled to fit data:

CCF(s)

$\chi^2(s)$

$\chi^2_{\min} \sim N$

1σ error bar: $\Delta\chi^2 = \chi^2 - \chi^2_{\min} = 1$



Project 2 = Keck Spectra of a Black-Hole Binary

13 spectra from Keck
10m on Mauna Kea.

Fit continuum.

Cross-correlate with
template star spectra.

Measure 13 radial
velocities.

Fit sine curve to
measure velocity semi-
amplitude.

Work out constraints on
the black hole mass.

